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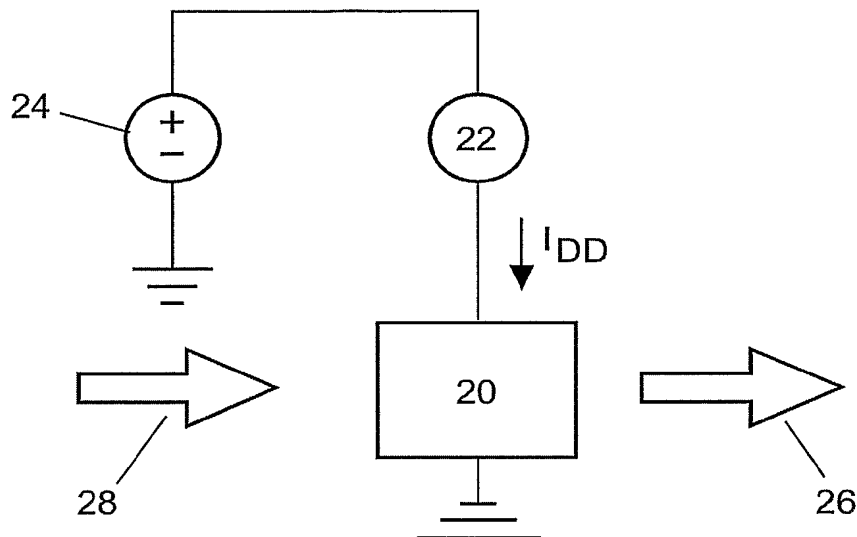
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(54) Title: METHOD AND DEVICE FOR TESTING A PHASE LOCKED LOOP



(57) Abstract: Testing device for testing a phase locked loop having a power supply input, said testing device comprising: a power supply unit for providing a power supply signal V_{DD} having a variation profile to the power supply input of the phase locked loop, wherein a width and height of said variation profile are formed in such a way, that the voltage controlled oscillator is prevented from outputting an oscillating output signal U_{osc} , a means for disabling a feedback signal to a phase comparator of the phase locked loop such that said phase locked loop is operated in an open loop mode, and a meter for measuring a measurement signal of the phase locked loop, while said power supply signal is provided to the power supply input.

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